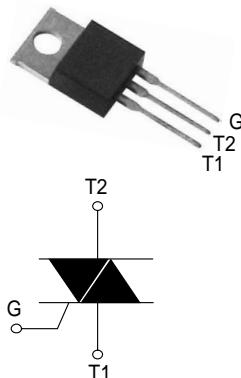
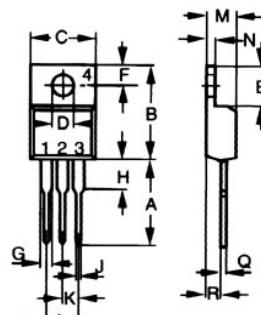


BTB/BTA06

Discrete Triacs(Non-Isolated/Isolated)



Dimensions TO-220AB



Dim.	Inches		Millimeter	
	Min.	Max.	Min.	Max.
A	0.500	0.550	12.70	13.97
B	0.580	0.630	14.73	16.00
C	0.390	0.420	9.91	10.66
D	0.139	0.161	3.54	4.08
E	0.230	0.270	5.85	6.85
F	0.100	0.125	2.54	3.18
G	0.045	0.065	1.15	1.65
H	0.110	0.230	2.79	5.84
J	0.025	0.040	0.64	1.01
K	0.100	BSC	2.54	BSC
M	0.170	0.190	4.32	4.82
N	0.045	0.055	1.14	1.39
Q	0.014	0.022	0.35	0.56
R	0.090	0.110	2.29	2.79

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter			Value	Unit
$I_T(\text{RMS})$	RMS on-state current (full sine wave)	TO-220AB	$T_c = 100^\circ\text{C}$	6	A
I_{TSM}	Non repetitive surge peak on-state current (full cycle, T_j initial = 25°C)	$F = 60 \text{ Hz}$	$t = 16.7 \text{ ms}$	63	A
		$F = 50 \text{ Hz}$	$t = 20 \text{ ms}$	60	
I^2t	I^2t Value for fusing	$t_p = 10 \text{ ms}$		21	A^2s
dI/dt	Critical rate of rise of on-state current $ I_G = 2 \times I_{GT} , t_r < 100 \text{ ns}$	$F = 120 \text{ Hz}$	$T_j = 125^\circ\text{C}$	50	$\text{A}/\mu\text{s}$
I_{GM}	Peak gate current	$t_p = 20 \mu\text{s}$	$T_j = 125^\circ\text{C}$	4	A
$P_{G(AV)}$	Average gate power dissipation		$T_j = 125^\circ\text{C}$	1	W
T_{stg} T_j	Storage junction temperature range Operating junction temperature range			- 40 to + 150 - 40 to + 125	$^\circ\text{C}$

ELECTRICAL CHARACTERISTICS ($T_j = 25^\circ\text{C}$, unless otherwise specified)

■ SNUBBERLESS™ and LOGIC LEVEL(3 Quadrants)

Symbol	Test Conditions	Quadrant		BTA/BTB		Unit
				CW	BW	
$I_{GT}(1)$	$V_D = 12 \text{ V}$ $R_L = 30 \Omega$	I - II - III	MAX.	35	50	mA
V_{GT}		I - II - III	MAX.	1.3		V
V_{GD}	$V_D = V_{DRM}$ $R_L = 3.3 \text{ k}\Omega$ $T_j = 125^\circ\text{C}$	I - II - III	MIN.	0.2		V
$I_H(2)$	$I_T = 100 \text{ mA}$		MAX.	35	50	mA
I_L	$I_G = 1.2 I_{GT}$	I - III	MAX.	50	70	mA
		II		60	80	
$dV/dt(2)$	$V_D = 67\% V_{DRM}$ gate open $T_j = 125^\circ\text{C}$		MIN.	400	1000	$\text{V}/\mu\text{s}$
(dI/dt)c (2)	Without snubber $T_j = 125^\circ\text{C}$		MIN.	3.5	5.3	A/ms

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Discrete Triacs(Non-Isolated/Isolated)

■ STANDARD (4 Quadrants)

Symbol	Test Conditions	Quadrant		Value	Unit
I _{GT} (1)	V _D = 12 V R _L = 30 Ω	I - II - III	MAX.	50	mA
V _{GT}		IV	MAX.	100	
V _{GD}	V _D = V _{DRM} R _L = 3.3 Ω T _j = 125°C	ALL	MIN.	0.2	V
I _H (2)	I _T = 500 mA		MAX.	50	mA
I _L	I _G = 1.2 I _{GT}	I - III - IV	MAX.	50	mA
		II		100	
dV/dt (2)	V _D = 67 % V _{DRM} gate open T _j = 125°C		MIN.	400	V/μs
(dV/dt)c (2)	(dI/dt)c = 2.7 A/ms T _j = 125°C		MIN.	10	V/μs

STATIC CHARACTERISTICS

Symbol	Test Conditions			Value	Unit
V _{TM} (2)	I _{TM} = 5.5 A tp = 380 μs	T _j = 25°C	MAX.	1.55	V
V _{to} (2)	Threshold voltage	T _j = 125°C	MAX.	0.85	V
R _d (2)	Dynamic resistance	T _j = 125°C	MAX.	60	mΩ
I _{DRM}	V _{DRM} = V _{RRM}	T _j = 25°C	MAX.	5	μA
		T _j = 125°C		1	mA

Note 1: minimum IGT is guaranteed at 5% of IGT max.

Note 2: for both polarities of A2 referenced to A1

THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
R _{th(j-c)}	Junction to case (AC)	1.8	°C/W
R _{th(j-a)}	Junction to ambient	60	°C/W

PRODUCT SELECTOR

Part Number	Voltage (xxx)		Sensitivity	Type	Package
	200 V ~ 1000 V				
BTB/BTA06	X	X	50 mA	Standard	TO-220AB

OTHER INFORMATION

Part Number	Marking	Weight	Base quantity	Packing mode
BTB/BTA06	BTB/BTA06	2.3 g	250	Bulk



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Discrete Triacs(Non-Isolated/Isolated)

Fig. 1 Maximum power dissipation versus RMS on-state current (full cycle).

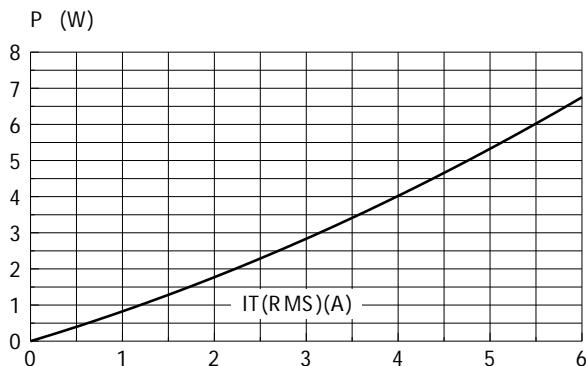


Fig. 3 Relative variation of thermal impedance versus pulse duration.

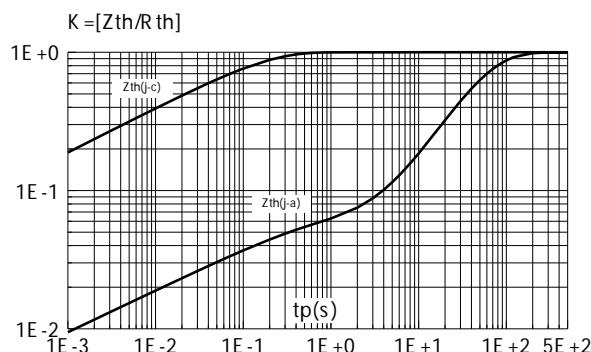


Fig. 5 Surge peak on-state current versus number of cycles.

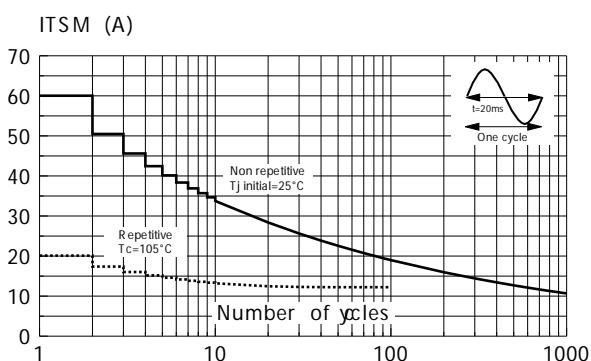


Fig. 2 RMS on-state current versus case temperature (full cycle).

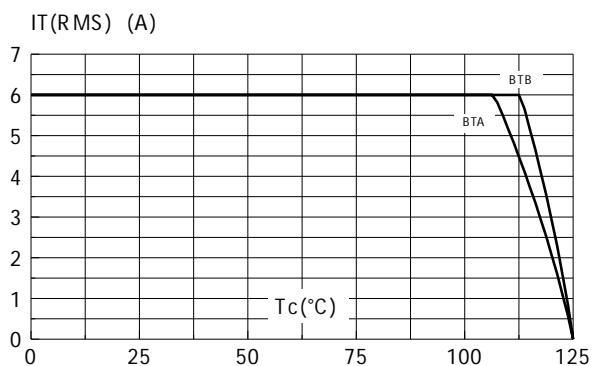


Fig. 4 On-state characteristics (maximum values).

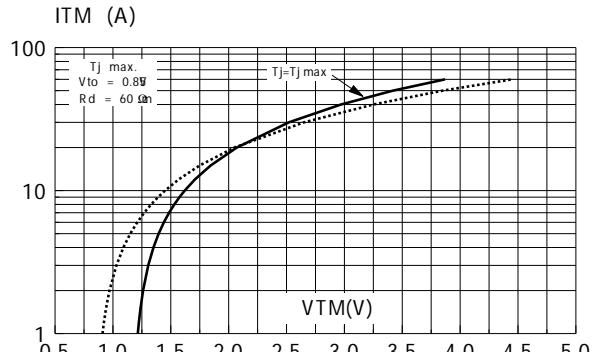
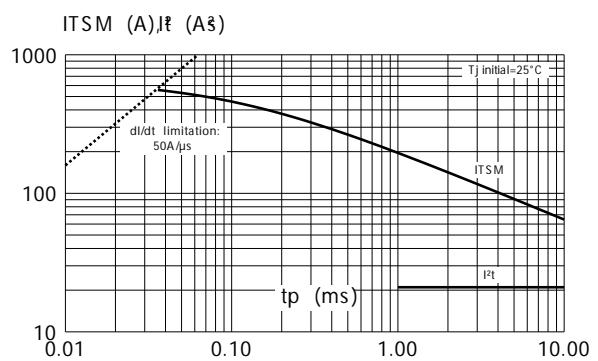


Fig. 6 Non-repetitive surge peak on-state current for a sinusoidal pulse with width tp < 10ms, and corresponding value of I²t.



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Discrete Triacs(Non-Isolated/Isolated)

Fig. 7 Relative variation of gate trigger current, holding current and latching current versus junction temperature (typical values).

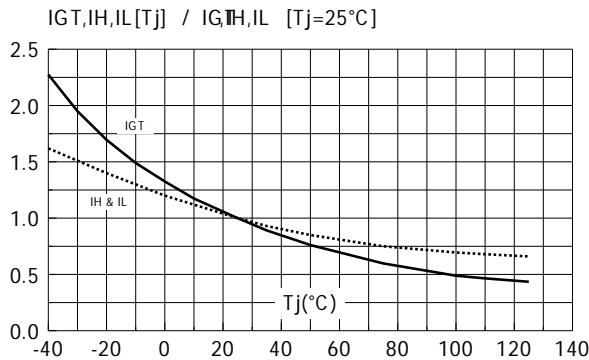


Fig. -8: Relative variation of critical rate of decrease of main current versus $(dV/dt)_c$ (typical values). S nubberless & Logic Level Types

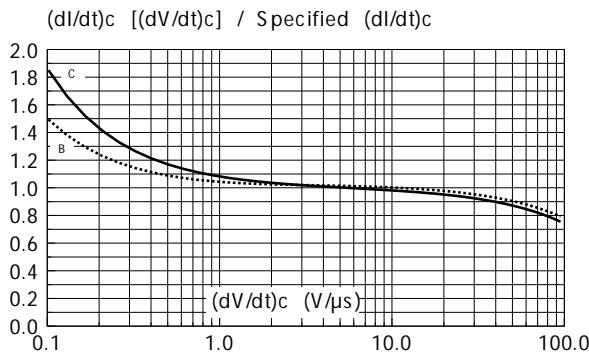


Fig. -8: Relative variation of critical rate of decrease of main current versus $(dV/dt)_c$ (typical values). S nubberless & Logic Level Types

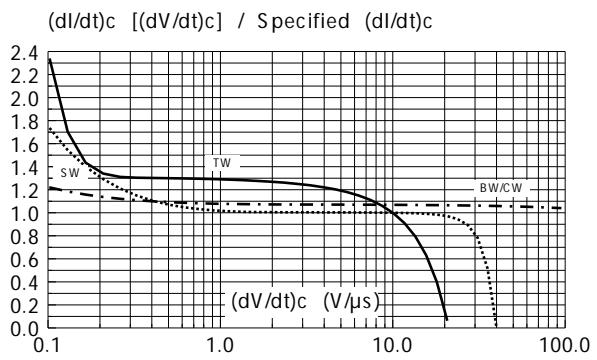


Fig. : 9 Relative variation of critical rate of decrease of main current versus junction temperature.

